Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,726	OGAWA, HIDEHIKO	
Examiner	Art Unit	
Thomas D. Lee	2625	

SEARCHED					
Class	Subclass	Date	Examiner		
358	1.15, 402, 440	9/22/2006	TDL		
379	100.01	9/22/2006	TDL		
379	100.08	9/22/2006	TDL		
379	100.13	9/22/2006	TDL		
379	100.17	9/22/2006	TDL		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	

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